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The inputs are buffered to lower the drive requirements to one series 74 or 74LS standard load, respectively. Input clamping diodes minimize switching transients and simplify system design. This parallel-in or serial-in, serial-out shift register has a complexity of 77 equivalent gates on a monolithic chip. This device features gated clock inputs and an overriding clear input.

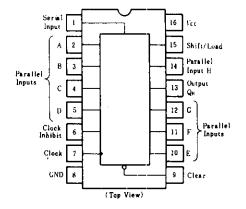
The parallel-in or serial-in modes are established by the shift/ load input.

When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When low, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse, During parallel loading, serial data flow is inhibited.

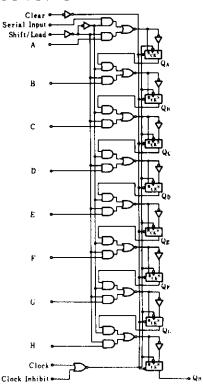
Clocking is accomplished on the low-to-high-level edge of the clock pulse through a two-input positive NOR gate permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs high inhibits clocking; holding either low enables the other clock input.

This, of course, allows the system clock to be free-running and the register can be stopped on command with the other clock input. The clock-inhibit input should be changed to the high level only while the clock input is high. A buffered, direct clear input overides all other inputs, including the clock. and sets all flip-flops to zero.

IPIN ARRANGEMENT



BBLOCK DIAGRAM



IFUNCTION TABLE

Inputs							rnal	Outputs	
	Shift	Clock Sarial	C1 - 1		Parallel	Outputs		Outputs	
Clear	Load		AH	QA	Qв	Qн			
L	Х	X	X	Х	Х	L	L	L	
Н	X	L	L	X	Х	QAO	QBO	Q _{HO}	
Н	L	L	Ť	Х	ah	a	Ъ	h	
Н	Н	L	†	Н	Х	Н	QAn	QGn	
Н	Н	L	1	L.	Х	L	QAn	Q _G n	
Н	Х	Н	†	X	X	QAO	QBO	QHO	

- Notes) I. H; high level, L; low level, X; irrelevant
 - 2. †; transition from low to high level
 - 3. 4; transition from high to low level
 - 4. a~h; the level of steady-state input at inputs A to H respectively
 - 5. QA0~QH0; the level of QA to QH, respectively, before the indicated steady-state input conditions were established.
 - 6. QAn~QHn; the level of QA to QH, respectively, before the most recent 4 transition of the clock.

ERECOMMENDED OPERATING CONDITIONS

ltem .	Symbol	min	nom	max	Unit
High level output current	Іон	_	-	-400	μA
Low level output current	Ior.	-	<u> </u>	8	mA
Clock frequency	fclock	0	_	25	MHz
Clock and clear pulse width	Lu	20	_	-	ns
Mode control seup time	t _{eu}	30		_	ns
Data setup time	teu	20	_	_	ns
Hold time	th	0			ns

BELECTRICAL CHARACTERISTICS ($Ta = -20 \sim +75 ^{\circ} \mathrm{C}$)

Item	Symbol	Test Condition	s	min	typ*	max	Unit
	VIH			2.0		· · · · · · · · · · · · · · · · · · ·	V
Input voltage	V _{IL}					0.8	V
	Von	$V_{CC} = 4.75 \text{ V}, V_{IH} = 2 \text{ V}, V_{IH} = 0.8 \text{ V}, I_{OH} = -400 \mu\text{A}$		2.7		-	V
Output voltage		$V_{CC} = 4.75 \text{V}, V_{IH} = 2 \text{V}$	$I_{OL} = 4 \text{mA}$			0.4	V
	Voi	$V_{fL}=0.8V$	Io L == 8m A			0.5	V
4000	Iн	$V_{CC} = 5.25 \text{V}, \ V_I = 2.7 \text{V}$			-	20	μA
Input current	In.	$V_{CC} = 5.25 \text{V}, V_I = 0.4 \text{V}$		-		-0.4	mĄ
•	- Ii	$V_{CC} = 5.25 \text{V}, \ V_I = 7 \text{V}$	W. Lyura . a			0.1	m A
Short-circuit output current	los	$V_{CC} = 5.25 \text{V}$		- 20		100	mΑ
Supply current**	lee	$V_{CC} = 5.25 \text{V}$			20	32	mΑ
Input clamp voltage	Vik	$V_{CC} = 4.75 \text{V}, I_{LN} = 18 \text{mA}$				1.5	V

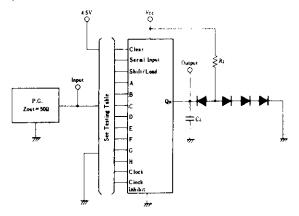
^{*} VCC=5V, Ta=25°C

ESWITCHING CHARACTERISTICS ($V_{CC} = 5V$, $T_a = 25^{\circ}C$)

Item	Symbol	Inputs	Test Conditions	min	typ	max	Unit
Maximum clock frequency	- Jmux			25	35		MHz
	tent.	Clear	$C_L = 15 \mathrm{pF}$		19	30	ns
Propagation delay time	tpht.		$R_L = 2 \mathrm{k} \Omega$	7	14	25	ns
	trun	Clock		5	11	20	ns

TESTING METHOD

1) Test Circuit



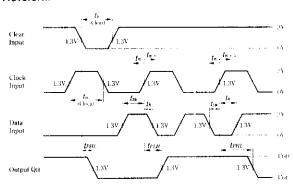
Notes) 1. C_L includes probe and jig capacitance.

2. All diodes are 1S2074 (H).

2) Testing Table

Data inputs	Shift/Load	Output	Bit time	
Data H	0V	Qн	t _{n+1}	
Serial-in	4.5V	Qн	tn+8	

Waveform



Notes) 1. Input pulse: $t_{TLH} \le 15 \text{ ns}$, $t_{THL} \le 6 \text{ ns}$, PRR = 1 MHzduty cycle 50%

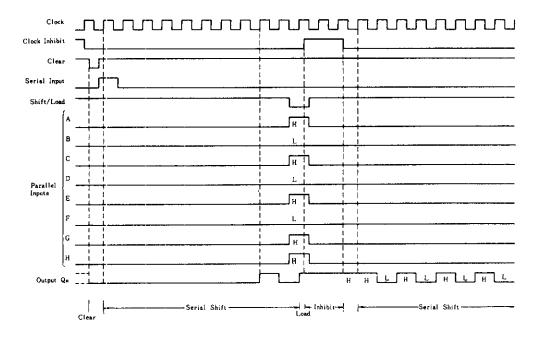
Clock input: $t_{w} \ge 20$ ns Clear input: $t_{w} \ge 20$ ns, $t_{h} = 10$ ns, when testing f_{max} , vary the clock PRR.

2. Propagation delay time (t_{PLH}) and t_{PHL} are measured at t_{n+1} . Proper shifting of data is verified at t_{n+8} with a functional test.

3. t_n ; bit time before clocking transition. t_{n+1} ; bit time after one clocking transition. t_{n+8} ; bit time after eight clocking transition.

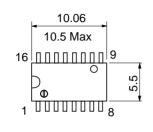
^{**} With all outputs open, 4.5V applied to the serial input and all other inputs except the clock grounded, I_{CC} is measured after a momentary ground, then 4.5V, is applied to clock.

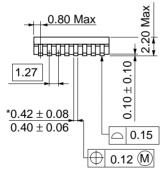
■TYPICAL CLEAR, SHIFT, LOAD, INHIBIT, AND SHIFT SEQUENCES

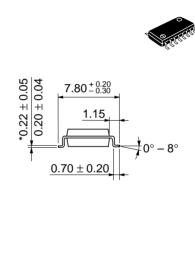


Unit: mm 19.20 20.00 Max 16 7.40 Max 6.30 1.3 1.11 Max 7.62 5.06 Max 2.54 Min 0.51 Min $0.25^{+0.13}_{-0.05}$ 0.48 ± 0.10 2.54 ± 0.25 $0^{\circ} - 15^{\circ}$ Hitachi Code DP-16 **JEDEC** Conforms EIAJ Conforms Weight (reference value) 1.07 g

Unit: mm







*Dimension including the plating thickness
Base material dimension

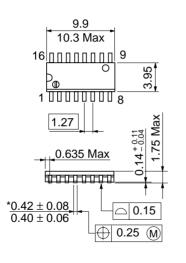
EIAJ Conforms
Weight (reference value) 0.24 g

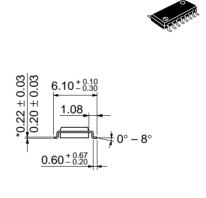
FP-16DA

Hitachi Code

JEDEC

Unit: mm





*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

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